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Ferroelectricity Newsletter

A quarterly update on what's happening in the field of ferroelectricity

Volume 10, Number 3

Summer 2002

NARA CONFERENCE COMBINES STATE-OF-THE-ART TECHNOLOGY UPDATE WITH CULTURAL ENRICHMENT

Against a background infused with cultural treasures and scenic beauty, two important international symposia on the applications of ferroelectrics — **International Symposium on the Applications of Ferroelectrics (ISAF)** and **International Symposium on Integrated Ferroelectrics (ISIF)** — joined with Japan's domestic meeting on **Ferroelectric Materials and their Applications (FMA)** in the **International Joint Conference on the Applications of Ferroelectrics 2002 (IFFF 2002)**. During the last days of May, scientists and engineers gathered in Nara, the capital of Japan in ancient times, to exchange and discuss the latest findings in the field of applications of ferroelectric, piezoelectric, dielectric, electrooptic single crystals, polycrystalline ceramics, and films.

In this issue we list the titles and authors of all oral presentations, covering the following topics: Thin films (p. 2), piezoelectrics (p. 5), FeRAM & devices (p. 6), characterization (p. 7), domain & switching (p. 8), fundamentals (p. 8), relaxors (p. 9), optics (p. 9), micro ferroelectrics (p. 9), dielectrics (p. 10), pyroelectrics (p. 10), high-k and gate oxides (p. 11), device integration (p. 11), and microwave devices (p. 11). On pages 12 through 18 you'll find the listing of a portion of poster presentations on various topics concerning thin films. The rest of the poster presentation listing will be published in the next issue of the *Ferroelectricity Newsletter*.

What made IFFF 2002 in Nara memorable for me was the combination of the high standard of technical information in an atmosphere of friendly and competent helpfulness with experiences of rich cultural beauty.

As usual, we bring you several announcements of upcoming meetings, such as the **Non-Volatile Memory Technology Symposium** in Hawaii, the **15th International Symposium on Integrated Ferroelectrics** in Colorado next March, the **3rd Asian Meeting on Electroceramics** in summer 2003 in Singapore, a conference on **Polar Oxides** on Capri, Italy, and the **4th Asian Meeting on Ferroelectrics** in December 2003 in India. The **Calendar of Events** on the back page provides an overview of all the meetings through December 2003 we heard about. If you know of a conference not listed, please send us the information and we'll be happy to include it in future issues.

Rudolf Panholzer
Editor-in-Chief

IN THIS ISSUE

| | |
|---|-----------|
| From the Editor | 1 |
| Papers | |
| IFFF 2002 | 2 |
| Upcoming Meetings | |
| Smart Materials | 19 |
| Nonvolatile Memory | 20 |
| ISIF 2003 | 20 |
| 3rd Asian Meeting on Electroceramics | 21 |
| Polar Oxides | 22 |
| AMF-4 (2003) | 22 |
| Asian Ferroelectric Association | 23 |
| Calendar of Events | 24 |

Ferroelectricity Newsletter

Volume 10, Number 3
Summer 2002

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| IFFF 2002 PAPERS |
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INTERNATIONAL JOINT CONFERENCE ON THE APPLICATIONS OF FERROELECTRICS (IFFF 2002)

The international joint conference on the applications of ferroelectrics was held at Nara, Japan, from 28 May to 1 June 2002. At this memorable occasion, the world's most important international symposia on the application of ferroelectrics, the **IEEE International Symposium on the Applications of Ferroelectrics (ISAF XIII 2002)** and the **International Symposium on Integrated Ferroelectrics (ISIF XIV 2002)**, joined together for the first time and each of them was held in Japan for the first time. The meeting on **Ferroelectric Materials and Their Applications (FMA XIX 2002)**, Japan's domestic meeting dedicated to ferroelectric materials and their applications since 1977, was the third partner in this joint international ferroelectrics conference called **IFFF 2002**.

IFFF 2002 Proceedings

The proceedings of the international joint conference will be published in the following journals:

Proceedings:
ISAF XIII 2002
ISIF XIV 2002
FMA XIX 2002

Published in:
IEEE Proceedings
Integrated Ferroelectrics
Japanese Journal of Applied Physics

The following is a list of oral and poster presentations given at IFFF 2002, arranged according to topics.

PLENARY

The downscaling of piezoelectric and pyroelectric ceramics:
 Microdevices, nanofabrication and size effects
N. Setter

Does memory of dream come true?
 (Market prospects and technical hurdles for FRAM)
H. Nishi

THIN FILMS

A mass production compatible metalorganic chemical vapor deposition process of $\text{Pb}(\text{Zr,Ti})\text{O}_3$ thin films at low temperatures
S. Jeong, J.-S. Zhao, J. Lim, and C.S. Hwang

Impact of thickness and A-site stoichiometry on the reliability of MOCVD $\text{Pb}(\text{Zr,Ti})\text{O}_3$ thin films
D.V. Taylor, S.R. Gilbert, D. Ritchey, J. Amano, S. Aggarwal, T. Sakoda, T.S. Moise, S.R.

Summerfelt, F. Celi, J. Rodriguez, S. Martin, and K.J. Taylor

Reproducibility of MOCVD-PZT thin films in the long term continuous running by PZT-MOCVD production module
T. Yamada, T. Masuda, M. Kajinuma, H. Uchida, M. Uematsu, K. Suu, and M. Ishikawa

$\text{Pb}(\text{Zr,Ti})_3$ thin films deposited by MOCVD for embedded memory technology
S. Aggarwal, S. Martin, F. Celi, L. Hall, J. Rodriguez, K.R. Udayarkumar, S.R. Summerfelt, T.S. Moise, and K.J. Taylor

Growth of PZT thin films by LS-MOCVD for high density FeRAM application
J.K. Lee, M.-S. Lee, S. Hong, W. Lee, Y.K. Lee, and Y. Park

Electrical properties of dielectric and ferroelectric films prepared by plasma enhanced atomic layer deposition
W.-J. Lee, B.-G. Chae, S.-O. Ryu, I.-K. Yu, S.M. Cho, B.-G. Yu, and K.-I. Cho

Characterization of PLZT film capacitor degradation in reducing ambients using a newly developed *in-situ* prober
J.S. Cross and M. Tsukada

Dielectric and polarization characteristics of sol-gel derived lead zirconate titanate thin films: Effect of erbium doping
R.S. Katiyar, A. Dixit, B. Roy, W. Jia, and S.B. Majumder

Lead content control in PZT films by using Ar/O_2 sequential crystallization annealing
O. Arisumi, S. Nakamura, B.K. Moon, K. Yamakawa, and K. Imai

IFFF 2002 PAPERS

Effect of textured $\text{Pb}(\text{Zr}_{1-x}\text{Ti}_x)\text{O}_3$ seed layer on fatigue improvement of ferroelectric

$\text{Pb}_{0.99}(\text{Zr}_{0.6}\text{Sn})_{0.85}\text{Ti}_{0.15}\text{Nb}_{0.02}\text{O}_3$ thin films

K.H. Yoon, H.C. Shin, and D.H. Kang

Role of fluorite formation in orientation selection in sol-gel derived PZT films on PT electrode layers

G.J. Norga, L. Fe, F. Vasiliu, and O. Van der Bies

Relationship between orientation and ferroelectric properties in Ir/PZT/Ir epitaxial capacitors

K. Okuwada, J. Ishida, T. Yamada, A. Sawabe, and K. Saito

Development of materials integration strategies for electroceramic film-based devices via complementary *in situ/ex situ* studies of film and interface processes

O. Auciello, A.H. Muller, E.A. Irene, A.M. Dhotel, and R. Ramesh

$\text{Ln}(\text{Ln}=\text{La, Pr, Nd, Sm})$ dependence on ferroelectric property for $(\text{Bi}_{3.25}\text{Ln}_{0.75})(\text{Ti}_{2.97}\text{V}_{0.03})\text{O}_{12}$ thin films prepared at low deposition temperature

T. Sakai, T. Watanabe, T. Kojima, M. Osada, Y. Noguchi, M. Miyayama, and H. Funakubo

Both ohmic contact properties of tungsten plug and ferroelectric properties of $(\text{Bi,La})_4\text{Ti}_3\text{O}_{12}$ thin film in stacked capacitor structure

S.-Y. Kweon, N.-K. Kim, E.-S. Choi, S.-J. Yoom, and J.-S. Rob

Ferroelectric characteristics of $\text{Bi}_{4-x}\text{La}_x\text{Ti}_3\text{O}_{12}$ thin films crystallized at low temperatures

K. Tanaka, T. Uno, and Y. Shimada

Sol-gel hydrothermal synthesis of barium strontium titanate thin films

K. Zalonka, M. Sayer, H. Hammad, and A.P. Freundorfer

Domain structures in epitaxial PZT thin films

S. Baik

Electrical properties of epitaxial $(\text{Pb,Sr})\text{TiO}_3$ thin films prepared by RF magnetron sputtering

J. Du, T. Karaki, T. Fujii, and M. Adachi

Ferroelectric property of PZT (001) thin film deposited on epitaxial $(\text{Ni,Zn,Fe})\text{Fe}_2\text{O}_4(111)$ thin film for novel ferroelectric/ferromagnetic memory applications

N. Wakiya, K. Shimozaki, and N. Mizutani

Crystallization of zirconium-rich PLZT thin films below 500°C

M. Mandeljc, B. Malic, M. Kosec, and G. Drazic

Microstructure and electrical properties of PZT thin films deposited by laser ablation on template layer

Z.J. Wang, H. Kokawa, and R. Maeda

The properties of multilayered $\text{Pt}(\text{Ba}_{0.5}\text{Sr}_{0.5}\text{TiO}_3/\text{Pb}(\text{Zr}_{0.52}\text{Ti}_{0.48})\text{O}_3)/(\text{Ba}_{0.5}\text{Sr}_{0.5})\text{TiO}_3/\text{Pt}$ thin films

F. Yan, P. Bao, J. Zhu, and Y. Wang

The influence of bottom electrodes and seed islands on the epitaxial growth characteristics of SBT thin

films

S.-Y. Jung, W.-C. Kwak, G.M.A. Kumar, Y.-M. Sung, and S.-J. Hwang

Preparation of $\text{SrBi}_2\text{Ta}_2\text{O}_9$ ferroelectric thin films by RF magnetron sputtering

Y. Nishioka and H. Ishiwara

Development of 500\AA thick MOCVD SBT films for $0.18\mu\text{m}$ FeRAM process

S. Narayan, V. Joshi, M. Lim, C.A. Paz de Araujo, L.D. McMillan, K. Uchiyama, Y. Shimada, S. Miedl, F. Schienle, M. Schumacher, and J. Juergensen

Improvement in ferroelectric properties of $\text{SrBi}_2\text{Ta}_2\text{O}_9$ thin films with Bi_2O_3 buffer layers by liquid delivery metalorganic chemical vapor deposition

N.-J. Seong, W.-C. Shin, K.-J. Choi, and S.G. Yoon

Electrode size effect on switching time of $\text{SrBi}_2\text{Ta}_2\text{O}_9$ thin films

X.B. Chen, F. Yan, C.H. Li, J.S. Zhu, and Y.N. Wang

Modeling of thickness effect on the dielectric properties of BST thin films

A.I. Kingon, C. Parker, J.-P. Maria, and S.K. Streiffner

Influence of strains and defects on ferroelectric and dielectric properties of thin film barium strontium titanates

D. Balzar, P.A. Ramakrishnan, P. Spagnol, S. Mani, and A.M. Hermann

IFFF 2002 PAPERS

Microstructures and dielectric properties of compositionally graded $(\text{Ba}_{1-x}\text{Sr}_x)\text{TiO}_3$ thin films prepared by pulsed laser deposition
X. Zhu, H.L.-W. Chan, C.-L. Choy, and K.-H. Wong

Microstructural and electrical properties of $(\text{Ba}_x\text{Sr}_{1-x})\text{Ti}_{1+y}\text{O}_{3+z}$ thin films prepared at low temperatures ($T < 450^\circ\text{C}$) by RF magnetron sputtering
J.D. Baniecki, T. Shioga, and K. Kurihara

Thickness dependent properties of barium strontium titanate between 15 and 600nm
J.-P. Maria, C.B. Parker, G. Stauff, and A.I. Kingon

Leakage current measurements of STO and BST thin films interpreted by the "dead layer" model
S. Schmitz and H. Schroeder

The effects of post oxygen plasma treatment on Pt/(Ba,Sr)TiO₃/Pt capacitors at low substrate temperatures
J.-L. Wang, C.-C. Hwang, D.-C. Shye, M.-J. Lai, C.-C. Jaingl, J.-S. Chen, S. Huang, M.-H. Juang, B.-S. Chiou, and H.-C. Cheng

Chemical approach using tailored liquid sources to traditional and novel ferroelectric thin films
K. Kato, K. Suzuki, D. Fu, K. Nishizawa, and T. Miki

Annealing temperature dependence of crystallinity, strain, and memory effects of SrBi₂Ta₂O₉/SiN/Si structure
J.-P. Han, C.J. Xie, K.-H. Kim, C.C. Broadbridge, D.L. Pechkis,

Y.X. Liu, W. Tong, A.H. Lehman, and T.P. Ma

Oxygen barrier for stacked SBT-FECAP on W-plug
J. Lisoni, D. Maes, J.-L. Everaert, J. Johnson, V. Paraschiv, L. Haspeslagh, D.J. Wouters, P. Casella, C. Corvasce, R. Zambrano, H. Monchoix, and L.V. Autryve

Effect of cation substitution on the crystallization kinetics of sol-gel derived SBT thin films
W.-C. Kwak, S.-Y. Jung, G.M.A. Kumar, S.-J. Hwang, and Y.-M. Sung

Low temperature crystallization of SrBi₂Ta₂O₉ (SBT) in the ultra thin film region fabricated by MOCVD
K. Uchiyama, S. Narayan, Y. Shimada, L. McMillan, and C.A. Araujo

Bias sputtering as a tool for processing textured ferroelectric film
M. Maglione and J.P. Manaud

Characterization of sol-gel derived Bi_{4-x}La_xTi₃O₁₂ films
N. Sugita, T. Suzuki, E. Tokumitsu, and M. Osada

Dielectric properties of CaCu₃Ti₄O₁₂ thin film
K.Y. Cho, N.J. Wu, and A. Ignatiev

Preparation and application of PZT thin films deposited by hybrid processes: Sol-gel method and laser ablation
J.W. Wan, J.-J. Tsaour, Z.J. Wang, and R. Maeda

Stress induced phase transforma-

tions in (001) MOCVD-grown PZT thin films
M.B. Kelman and P.C. McIntyre

Preparation of ferroelectric Ba(Ti_{0.85}Sn_{0.15})O₃ thin films by metalorganic decomposition
T. Miyamoto, S. Murakami, K. Inoue, Y. Suzuki, T. Nomura, M. Noda, and M. Okuyama

Ferroelectric lead zirconate titanate thin films synthesized via a high-pressure crystallization process
C.-H. Lu and Y.-C. Sun

RF magnetron sputtered ferroelectric (Na,K)NbO₃ films
M. Blomqvist, J.-H. Koh, S.I. Khartsev, and A.M. Grishin

A new class of ferroelectrics suitable for 0.5 V operation of nonvolatile random access memory
T. Kijima and H. Ishiwara

High frequency LIMM: A powerful tool for ferroelectric thin film characterization
T. Sandner, G. Suchaneck, R. Koehler, and G. Gerlach

Investigation of the thermal stability of Pb₅Ge₃O₁₁ thin films and methods of improvement
F. Zhang, W. Zhuang, and S.T. Hsu

Characterization of rhombohedral (111) and (100) lead zirconate titanate films fabricated by RF magnetron sputtering
T. Fujii and M. Adachi

IFFF 2002 PAPERS

PIEZOELECTRICS

Critical issues in single crystal growth of PMN:PT by seeded polycrystal conversion

H.M. Chan and M.P. Harmer

On origin of the enhanced piezoelectric response along a nonpolar direction in simple perovskites

D. Damjanovic, F. Brem, and N. Setter

High temperature high performance materials

T.R. Shrout, R. Eitel, S. Zhang, C.A. Randall, P. Rehrig, and E. Alberta

Piezoelectric properties dependence on thickness of PZT films fabricated by aerosol deposition method

M. Lebedev and J. Akeda

Apparent reduction in the value of the d_{33} piezoelectric coefficient in PZT thick films

R.A. Dorey and R.W. Whatmore

Vibration characteristics of micromachined lead zirconate titanate diaphragms

E. Hong, S.V. Krishnaswamy, C.B. Freidhoff, and S. T.-McKinstry

Sound generation with piezoelectric actuators for active noise reduction applications

T. Morita, E.L. Colla, and N. Setter

Evaluation of low temperature processing of lead zirconate titanate (53/47) ceramics derived from 1-propanol based sol-gel stock solutions

L. Wu, B.-Huei Chen, T.-Y.

Chang, J. L.-Hunang, and C.L. Huang

Low temperature sintering of piezoelectric thick films derived from a novel sol-gel route

W. Zhu, Z.H. Wang, C.L. Zhao, and O.K. Tan

Processing and characterization of pressure consolidated lead-free piezoceramics based on alkaline niobates

C. Pithan, B. Malic, E. Ringgard, and R. Waser

Preparation of orientation-controlled $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ (PZT) thick films prepared by high-speed MOCVD and their properties

S. Yokoyama, T. Ozeki, T. Oikawa, Y. Ichikawa, Y. Yamachita, T. Ochiai, and H. Funakubo

Fine tolerance resonator applications of bismuth layer structured ferroelectric ceramics

A. Ando, T. Sawada, H. Ogawa, M. Kimura, and Y. Sakabe

Properties of $(\text{Na}_{1/2}\text{Bi}_{1/2})\text{Ti}_3\text{O}_{12} \cdot \text{Bi}_4\text{Ti}_3\text{O}_{12}$ piezoelectric ceramics

A. Sanson and R.W. Whatmore

$\text{Bi}_4\text{Ti}_3\text{O}_{12}$ -based lead-free piezoelectric ceramics with grain orientation

H. Nagata, Y. Yano, T. Enosawa, Y. Fujita, and T. Takenaka

Novel piezoelectric ceramic/polymer composite transducers

S. Turcu, B. Jadidian, S.C. Danforth, and A. Safari

Piezoelectric properties and structural characterization of

$(\text{Na},\text{Bi})\text{Bi}_2\text{Ta}_2\text{O}_9$ ceramics with bismuth layer structure

R. Ayoyagi, M. Matsushita, K. Komagata, H. Takeda, S. Okamura, and T. Shiosaki

Piezoelectric applications of ferroelectric single crystals

K. Nakamura

Dielectric and piezoelectric properties of BaTiO_3 and PMN-PT single crystals grown from polycrystalline precursors

J.-B. Lee, T.-M. Heo, D.-H. Kim, H.-Y. Lee, and D.-Y. Kim

Dielectric and piezoelectric properties of $0.93\text{Pb}(\text{Zn}_{1/3}\text{Nb}_{2/3})\text{O}_3$ - 0.07PbTiO_3 single crystals for phased array

Y. Hoson, T. Kobayashi, K. Harada, K. Itsumi, M. Izumi, Y. Yamashita, and N. Ichinose

PZN-PT- and BS-PT-based high frequency single-element transducers for medical ultrasonic imaging

S. Rhee, S. Zhang, T. Shrout, and K.K. Shung

Nonlinear characterization of high power transducers

P. Gonnard and L. Petit

Potassium niobate single-domain crystals as the piezoelectrics with low dielectric and high electromechanical coupling properties

S. Wada, K. Muraoka, H. Kakemoto, H. Kumagai, and T. Tsurumi

The development of new high performance mechanical-electromechanical actuators

R.W. Schwartz and M.

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Narayanan

A 35 MHz linear ultrasonic array for medical imaging

J.M. Cannata, T.R. Shrout, and K.K. Shung

Piezoelectric transformer for 30W output AC-DC converters

M. Yamamoto, Y. Sasaki, T. Inoue, A. Ochi, and S. Hamamura

Design of a 50 MHz annular array using fine-grain lead titanate

K.A. Smook, T.R. Shrout, and K.K. Shung

Performance enhancement of tunable bandpass filters using selectively etched ferroelectric thin films

F. Miranda, C. Mueller, F. Van Keuls, R. Romanofsky, G. Subramanyam, and S. Vigneparamoorthy

Phase development and electrical properties of $\text{Pb}(\text{Yb}_{1/2}\text{Nb}_{1/2})\text{O}_3$ - PbTiO_3 epitaxial films

T. Yoshimura and S. T.-McKinstry

Hysteresis properties of PZT thin film bulk acoustic resonators

R. Gabl, M. Schreiter, R. Primig, and W. Wersing

Fabrications and resonant behavior of PZT thick film cantilever for biochips

H.J. Kim, Y.-B. Kim, J.-Y. Kang, and T.S. Kim

Ultrasonic phased array micro-sensor using piezoelectric PZT thin film and resonant frequency tuning

by poling

K. Yamashita, T. Fukunaga, M. Okuyama, S. Aoyagi, and Y. Suzuki

Integration of piezoelectric PZT thin films with internal electrodes into an actuator structure for MEMS applications

M. Hoffmann, C. Kügeler, U. Böttger, and R. Waser

Functionally gradient piezoelectric ceramics for ultrasonic transducers

S. Takahashi, N. Miyamoto, and N. Ichinose

FeRAM & DEVICES

Key technologies for high density FeRAM applications

N. Nagel

Scaling and performance issues of low temperature crystallized $\text{Pb}(\text{Zr,Ti})\text{O}_3$ thin films for high density FeRAM devices

S.-H. Kim, C.Y. Koo, D.-S. Lee, H.-J. Woo, D.-Y. Park, J. Yang, and J. Ha

A low temperature LNO/PZT/LNO ferroelectric capacitor-over-interconnect (COI) FeRAM module for advanced modular SOC

S.L. Lung, S.S. Chen, C.W. Tsai, T.T. Sheng, S.C. Lia, C.L. Liu, T.B. Wu, and R. Liu

The control of lead loss for PZT based FeRAM

F. Chu and G. Fox

Novel process integration of PZT capacitors for 35M FeRAM and beyond

K.M. Lee, K.S. Park, S.D. Nam,

S.W. Lee, S.H. Joo, H.G. An, H.J. Kim, M.S. Lee, S.O. Park, U.I. Chung, and J.T. Moon

Low thermal budget process of thin $\text{SrBi}_2\text{Ta}_2\text{O}_9$ film for 3V or lower voltage operation of high density FeRAM

M. Lim, V. Joshi, S. Narayan, J. Celinska, Z. Chen, C.A. Paz de Araujo, and D.L. McMillan

Status and issues of FeRAM integration and characterization

Y.-J. Park

Comparison of MFOS one transistor memory devices

T. Li, S.T. Hsu, B. Ulrich, and D. Evans

A novel single-FET cell and array architecture for ferroelectric non-volatile memories

W.-Q. Zhang, T.-L. Ren, C.-X. Li, T.-Q. Shao, J. Zhu, L.-T. Liu, and Z.-J. Li

A 0.13 μm 1.5V 1T1C 4Mb embedded ferroelectric RAM with novel sense-amplifier and plate-line architecture

J. Rickes, J. Grace, J. Fong, S. Gilbert, C. Pietrzyk, R. Lanham, J. Amano, S. Summerfelt, and T. Moise

Advanced encapsulating barrier layer technology for 0.25 μm 1T1C 32MB FRAM

H.J. Joo, Y.J. Song, H.H. Kim, N.W. Jang, S.Y. Lee, Y.S. Park, and K. Kim

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| IFFF 2002 PAPERS |
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CHARACTERIZATION

In-situ synchrotron X-ray studies of metalorganic chemical vapor deposition of $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$ thin films

S.K. Streiffer, G.B. Stephenson, J. A. Eastman, D. Fong, M.E.M. Aanerud, C. Thompson, O. Auciello, G.-R. Bai, and L. Thompson

Annealing effect of photoelectron spectra in $\text{SrBi}_2\text{Ta}_2\text{O}_9$ films

M. Takahashi, K. Kodama, M. Noda, P. Hedblom, A. Grishin, and M. Okuyama

Electrical properties and microstructures of ferroelectric $\text{Pb}(\text{Zr,Ti})\text{O}_3$ thin films prepared by laser annealing

C.-F. Chou, H.-C. Pan, and C.C. Chu

Dielectric properties of capacitor materials in the optical frequency range

M. Biegalski and S. T.-McKinstry

Electronic structures of $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ thin films and single crystals by resonant soft X-ray emission spectroscopy

T. Higuchi, K. Kudoh, T. Takeuchi, Y. Masuda, S. Shin, and T. Tsukamoto

Scanning nonlinear dielectric microscopy: A high resolution tool for observing ferroelectric domains and nano domain

Y. Cho

Wafer-level testing of single 1T-1C ferroelectric memory cells

S. Tiedke, J. Rickes, T. Schmitz, and R. Waser

Photoinduced domain pinning and hysteresis changes in ferroelectric thin films studied by scanning force microscopy

A. Gruverman, A.I. Kingon, B.J. Rodriguez, and R.J. Nemanich

Novel numerical method to correct for both circuit distortions and passive layers effect affecting Sawyer-Tower ferroelectric thin films hysteresis measurements

R. Bouregba and G. Poullain

Role of non-180° domain switching in electric properties of $\text{Pb}(\text{Zr,Ti})\text{O}_3$ thin films

K. Saito, T. Oikawa, T. Kurosawa, T. Akai, and H. Funakubo

Thickness-dependent leakage current of (PVDF/PbTiO₃) pyroelectric bilayer thin film detectors

M.C. Kan, C.W. Wang, and Y.C. Chen

Application of scanning probe microscope (SPM) for novel characterization of ferroelectric capacitors

I. Chung, I. Yi, and M. Yastake

Depth profiling of ferroelectric thin films with high energy ion beam spectroscopy

T. Kaneko, S. Nomura, G. Kano, and M. Watamori

SPM investigation of the Pt/PZT interface in ultrathin ferroelectrics

X. Lu, F. Schlaphof, C. Loppacher, G. Suchanek, and I.M. Eng

Microstructural characterization of SrRuO_3 films deposited on Si using SrO as buffer layers

Y.X. Chen, J. Koike, T. Higuchi,

S. Iwashita, M. Ishida, and T. Shimoda

Electric field induced polarization reversal by scanning piezoelectric microscopy

V.V. Shvartsman, N.A. Pertsev, A.Yu. Emelyanov, and A.L. Kholkin

Models of electrode-dielectric interfaces in ferroelectric thin film devices

J.F. Scott and M. Dawber

Separation of the near interface regions from the bulk in a ferroelectric thin film

D.P. Chu, B.M. McGregor, Z.G. Zhang, P. Migliorato, K. Ohashi, K. Hasegawa, and T. Shimoda

New approach to thin film characterization by switching current analysis

V. Shur, I. Baturin, E. Shishkin, and M. Belousowa

Ferroelectric capacitor compact model including dynamic and temperature behavior

E. Supriyanto, I. Schultz, M. Ullmann, and H. Goebel

Impact of thickness on the dielectric and electrical properties of pulsed laser ablated $\text{SrBi}_2\text{Nb}_2\text{O}_9$ thin films

S. Battacharyya, P. Victor, and S.B. Krupanidhi

PbTiO_x nanotube observed by electron microscopy

J. Zhu, X. Zhu, K. Yang, Q. Li, G. Ma, Z. Liu, and N. Ming

Investigation of the electrical tunability of silver-niobate-tantalate

IFFF 2002 PAPERS

thick films

*F. Zimmermann, W. Menesklou,
and E. I.-Tiffée*

Doping effects in layer structured
Bi₄Ti₃O₁₂ ferroelectrics lattice
dynamics and property design
investigated by Raman spectroscopy

*M. Osada, M. Kakihana, Y.
Noguchi, M. Miyayama, T.
Watanabe, and H. Funakubo*

Nonlinear dielectric properties of
BaTiO₃/srTiO₃ superlattice

*L. Kim, J. Kim, D. Jung, Y.S.
Kim, and J. Lee*

Investigation of the polyetherketone
poled polymer with highly thermal
stability for electrooptical applica-
tions

*Q. Pan, C. Fang, Z. Qin, W. Shi,
Q. Gu, and X. Wu*

Dynamical aspects of retention and
its relation to fatigue in ferroelectric
thin films

*B.S. Kang, J.-G. Yoon, T.K.
Song, S. Seo, Y.W. So, and T.W.
Noh*

Ferroic glass ceramics

Y. Xi

Literally two-dimensional ferroelec-
tricity probed by SHG in ferroelec-
tric LB monolayers

*T.V. Murzina, Y.G. Fokin, T.V.
Misuryaev, O.A. Aktsipetrov, S.P.
Palto, and S.G. Yudin*

Simultaneous measurement of
specific heat capacity, thermal
conductivity and thermal diffusivity
of ferroelectric ceramics by thermal
radiation calorimetry

K. Morimoto, A. Uematsu, S.

*Sawai, K. Hisano, and T.
Yamamoto*

Effect of copper substitution on the
dielectric and magnetic properties of
low-sintered Z-type hexaferrites

*X. Wang, J. Zhou, S. Su, Z. Gui,
and L. Li*

Dielectric spectra anomalies in
nanomaterials

*A.V. Ragulya, M.D. Glinchuk,
A.M. Slipenyuk, A.N.
Morozovskaya, I.P. Bykov, A.V.
Polotai, V.P. Klimenko, V.V.
Skorokhod, and C.A. Randall*

DOMAIN & SWITCHING

Influence of domain orientation and
grain size on PZT thin film proper-
ties

*B.A. Tuttle, G. Brennecke, P.G.
Clem, T.J. Boyle, J.D. Dawley,
M.A. Rodriguez, S. Streiffer, G.R.
Bai, O. Auciello, and R. Ramesh*

Model relating polarization switch-
ing and crystallographic texture of
PZT for FRAM applications

*G.R. Fox, S. Sun, and S.
Summerfelt*

Non-Kolmogorov-Avrami kinetics
of switching in ferroelectric thin
films

*A. Tagantsev, I. Stolichnov, E.
Colla, N. Setter, J.S. Cross, and
M. Tsukada*

A random-field model for ferroelec-
tric domain dynamics and polariza-
tion reversal

D. Viehland and J.F. Li

Spontaneous backswitching as a
perfect tool for nanoscale domain

patterning

*V. Shur, E. Rumyantsev, E.
Nikolaeva, E. Shishkin, D.
Fursov, R. Batchko, M. Fejer,
and R. Byer*

FUNDAMENTALS

A thermodynamic model for the
morphotropic phase boundary
region in lead zirconate titanate and
related materials

A.J. Bell

Improved mixing rule on permittiv-
ity

K. Wakino

Phenomenological theory of finite
size effects in nanophase ferroelec-
trics

E.K. Akdogan and A. Safari

First-principle calculations of the
new ferroelectric material SnTiO₃

*Y. Komishi, M. Ohsawa, and Y.
Yonezawa*

New accurate technique for solving
the LMM equation and a compari-
son with other methods

S.B. Lang

Defect engineering for control of
polarization properties in bismuth
layer structured ferroelectrics

*Y. Noguchi, M. Miyayama, K.
Oikawa, and T. Kamiyama*

Switching dynamics in ferroelectric
thin films: An experimental survey

*M. Dawber, P. Chandra, F.D.
Morrison, D.J. Jung, J.F. Scott,
L.J. Sinnamon, J.M. Gregg, Q.
Zhang, and R.W. Whatmore*

Contribution of Pb to ferroelectricity

IFFF 2002 PAPERS

in perovskite-type oxides

H. Miyazawa, E. Natori, M. Ishida, T. Shimoda, F. Ishi, and T. Oguchi

Crystal chemistry of bismuth-based ferroelectrics

D.I. Woodward, I.M. Reaney, A.R. West, and C.A. Randall

Bioferroelectricity and biomedicine: New results and approaches

V. Bystrov, N. Bystrova, G. Ovtchinnikova, Y. Pirigov, and Y. Dekhtyar

RELAXORS

Temperature and poling field dependencies of ferroelectric properties in $\text{Pb}[(\text{Zn}_{1/3}\text{Nb}_{2/3})_{0.91}\text{Ti}_{0.09}]\text{O}_3$ single crystals

T. Ogawa, Y. Yumamoto, and Y. Yamauchi

Temperature dependence of frequency and dielectric constants of pure and doped PbSZT ceramics in the morphotropic phase boundary

B. Guiffard, E. Boucher, L. Lebrun, and D. Guyomar

Epitaxial PMN-PT piezoelectric thick film heterostructures for high frequency medical ultrasound transducers

C.B. Eom, S.D. Bu, D.M. Kim, S.K. Streiffer, W. Tian, X.Q. Pan, T. Yoshimura, and S. Trolier-McKinstry

Top-seeded solution growth of $\text{Pb}[(\text{Zn}_{1/3}\text{Nb}_{2/3})_{0.93}\text{Ti}_{0.07}]\text{O}_3$ single crystals

T. Karaki, M. Nakamoto, and M. Adachi

Crystalline properties of ferroelec-

tric-relaxor PMN-PT thin films by pulsed laser deposition

S.K. Singh, P.A. Thomas, and S.B. Palmer

Production and growth of compositionally uniform single crystals of PMN-PT

P.W. Rehrig, W.S. Hackenberger, and T.R. Shrout

Dielectric dispersion and distribution of the relaxation times of the relaxor PLZT ceramics

J. Banys, A. Kajokas, A. Matulis, A. Brilingas, and J. Grigas

OPTICS

PLZT thin film optical waveguide devices

K. Nashimoto

Fabrication of Bragg diffraction-type acoustooptic device using piezoelectric PZT thin films

C. Lee, S. Kim, T.-H. Sung, and K. No

Ferroelectric thin film optical detectors for retinal prosthesis

A. Zomorrodian, N.J. Wu, S. Wilczak, A. Ignatiev, T. Bensaoula, and C.A. Garzia

Improvement of LiNbO_3 surface roughness by using a multistep process: Relationship between optical and AFM analysis

X. Lansiaux, E. Dogheche, and D. Rémiens

Ferroelectric switching and electroclinic effect in liquid crystals studied by second harmonic generation

Y.G. Fokin, T.V. Murzina, O.A. Aktsipetrov, S. Soria, and G. Marowsky

Defect controlled stoichiometric lithium niobate and lithium tantalate crystals for novel device

K. Kitamura and Y. Furukawa

A novel miniature optical switch array with cantilever micromirrors driven by PZT films

Y. Xu, T.-L. Ren, L.-T. Zhang, J.-S. Liu, L.-T. Liu, and Z.-L. Li

Nanosize inverted domain dot formation in stoichiometric LiTaO_3 single crystals using scanning nonlinear dielectric microscopy

Y. Hiranaga, Y. Cho, Y. Wagatsuma, K. Terabe, and K. Kitamura

Deflection of light under electric field in ferroelectric-ferroelastic AHSe crystals

Z. Czapla, S. Dacko, and P. Staniorowski

Holographic storage systems and materials

M. Zgonik

MICRO FERROELECTRICS

Ferroelectric nanostructures

M. Alexe, A. Visinoiu, C. Harnagea, D. Hesse, and U. Gösele

Size effect for lead zirconium titanate nanopowders with $\text{Pb}(\text{Zr}_{0.3}\text{Ti}_{0.7})\text{O}_3$ composition

T. Ohno, T. Mori, H. Suzuki, W. Wunderlich, M. Takahashi, and K. Ishikawa

IFFF 2002 PAPERS

Size effect in mesoscopic epitaxial ferroelectric structures: Increase of piezoelectric response with decreasing feature size

S. Bühlmann, B. Dwir, J. Baborowski, and P. Muralt

Nonlinearity of local electromechanical properties studied by scanning piezoelectric microscopy

V.V. Svartsman, N.A. Pertsev, P.M. Velarinho, and A.L. Kholkin

Compensation of the parasitic capacitance of an SFM cantilever used for measurements on ferroelectric capacitors of submicron size by means of finite element simulation

K. Prume, S. Tiedke, T. Schmitz, A. Roelofs, and R. Waser

Submicron scale size effect in PZT film capacitors: Polarization distribution anomalies and underlying mechanism

I. Stolichov, E. Colla, A. Tagantsev, S. Hong, B. Srowthi, N. Setter, J.S. Cross, and M. Tsukada

Metalorganic chemical vapor deposited electrodes for ferroelectric and high-permittivity oxide applications

P.K. Baumann, K. Fröhlich, O. Valet, P. Doppelt, F. Schienle, M. Schumacher, J. Lindner, G. Strauch, and H. Juergensen

DIELECTRICS

Recent topics in the field of material technology of BME-MLCCs

T. Nomura, M. Miyauchi, Y. Fujikawa, and Y. Nakamo

BaTiO₃ synthesis technique and its effect on BME dielectric formulations

D. McCauley, M. Chu, M. Megherhi, and E. Davis

Dielectric properties of fine-grained BaTiO₃ ceramics doped with CaO

Y. Sakabe, N. Wada, T. Hiramatsu, T. Tonogaki, and J. Tsujimoto

The effect of Ho/Mg ratio on formation of core-shell structure in BaTiO₃ and on dielectric properties of BaTiO₃ ceramics

A. Kirianov, T. Hagiwara, H. Kishi, and H. Ohsato

Dielectric properties of (Ba,Sr)O₃ MOD films grown on various substrates

P. Woo, I.P. Koutsaroff, M. Zelner, L. McNeil, J. Obeng, L. Chmiel, A. Kassam, B. McClelland, and A. C.-Lawry

Effect of occupational sites of rare earth elements on the Curie point in BaTiO₃

H. Kishi, N. Kohzu, N. Ozaki, H. Ohsato, and T. Okuda

The role of grain boundaries on the high temperature conduction behavior of titanate thin films and nanocrystalline ceramics

C. Ohly, S. Hoffmann-Eifert, and R. Waser

Dielectric properties of BaTiO₃ ceramics under high electric field

T. Tsurumi, H. Adachi, H. Kakemoto, S. Wada, H. Chazono, and H. Kishi

Dielectric properties of Ba(Mg_{1-x}Ta_x)-BaMg_{1-x}Nb_x

ceramics measured by terahertz and far-infrared spectroscopy

L.-N. Lin, Y.-C. Chen, H.-F. Cheng, T.-R. Tsai, and C.-C. Chi

Phase evolution and microwave dielectric properties of (Ba,Sr)O-Sm₂O₃ ceramics

T.J. Kim, J.-J. Kim, and H.Y. Lee

New dielectric material system with high temperature oxide superconductor

S. Sugihara, T. Kawashima, C. Ishizuka, and Y. Yutoh

PYROELECTRICS

High performance PST thin films on polysilicon sacrificial layers for uncooled IR detector arrays

C.J. Anthony, M.A. Todd, P.P. Donahue, and M.A.C. Harper

Pyroelectric barium strontium titanate thin films for uncooled thermal imaging

J.-G. Cheng, J. Tang, and J.-H. Chu

Thermal analysis of pyroelectric infrared sensors fabricated by a flip-chip transfer method

W.G. Liu, L.L. Sun, W. Zhu, O.K. Tan

Pyroelectric characterization of thin film PZT-Si structures with quadrant-diagonal electrode system as an element of position sensitive IR detector

S.L. Bravina, E. Cattani, N.V. Morozovsky, E. Fribourg-Blanc, and D. Remiens

Electrical properties of Er-doped BaTiO₃ ceramics for PTCR

M. Viviani, M.T. Buscaglia, V.

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Buscaglia, L. Mitoseriu, A. Testino, and P. Nanni

HIGH-k AND GATE OXIDES

High-k gate dielectrics for the silicon industry

L. Manchada

Fabrication and characterization of AlN thin films as gate dielectrics for silicon

J.H. Song, T. Chikyow, Y.Z. Yoo, P. Ahmet, K. Nakajima, T. Naruke, Y. Matsumoto, and H. Koimuna

Preparation by pulsed laser deposition and characterization of ZrO₂, HfO₂ and PrO_x thin films for high-k gate insulators

T. Kanashima, S. Kitai, M. Sohgewa, H. Kanda, and M. Okuyama

Al₂O₃/Si₃N₄ stacked insulator for advanced MOS FETS

Y. Fujisaki and H. Ishiwara

Hafnium nitrate precursor synthesis and hafnium oxide thin film properties

W. Zhuang, J.F. Conley, Jr., Y. Ono, D.R. Evans, and R. Solanki

Electrical properties of HfO₂ gate dielectric grown by plasma enhanced chemical vapor deposition in the absence of oxygen

K.-J. Choi, W.-C. Shin, J.-B. Park, and S.-G. Soon

DEVICE INTEGRATION

A constant reference bit-line voltage data sensing technique without reference cell for 1T1C FeRAMs

S. Kim, J.S. Kim, I.K. You, W.J. Lee, B.G. Yu, and H. Maes

Integration of FeRAM devices into a standard CMOS process: Impact of ferroelectric anneals on CMOS characteristics

M. Röhrner, T. Mikolajick, R. Hagenbeck, and N. Nagel

High temperature etching of PZT capacitor for FeRAM

M. Endo, M. Ueda, N. Hirai, S. Ishiwatari, H. Fujimoto, K. Watanabe, K. Sun, M. Ishikawa, J. Fujiyama, K. Suezawa, H. Kikuchi, G. Komuro, S. Mihara, and T. Yamazaki

High temperature plasma etching characteristics of submicron Ir/PZT/Ir ferroelectric capacitor stacks

S. Marks, L.G. Jerde, F.G. Celii, S.A. Aggarwal, and J.S. Martin

Electrical properties of nonvolatile latches for new logic application

Y. Fujimori, T. Nakamura, and H. Takasu

Oxygen diffusion barriers for high density FeRAMs

B.K. Moon, C.U. Pinnow, K. Imai, O. Arisumi, H. Itokawa, K.

Hornik, K. Tsutsumi, A. Hilliger, I. Kunishima, N. Nagel, K. Yamakawa, and G. Beitel

MICROWAVE DEVICES

Microwave tunable components and subsystems based on ferroelectrics: Physics and principles of design

O.G. Vendik

Enhanced dielectric properties of (Ba,Sr)TiO₃ thin films applicable to tunable microwave devices

B.H. Park and Q. Jia

Appearance mechanism of microwave dielectric property correlated with crystal structure

H. Ohsato, Y. Futamata, K. Kakimoto, and S. Nishigaki

The interplay between thin film ferroelectric microstructure and phase shifter performance

C. Mueller, F.V. Keuls, F. Miranda, and R. Romanofsky

Tunable integrated passive circuits using BST thin films

B. Acikel, H. Xu, J. Serraiocco, T.R. Taylor, P.J. Hansen, J.S. Speck, and R.A. York

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POSTERS

THIN FILM - FABRICATION - Pb SYSTEM

Properties of lead titanate thin films
*Z. Kighelman, D. Damjanovic,
M. Cantoni, and N. Setter*

Material properties of an epitaxial
PZT film on an epitaxial Ir/ZrN/
(100)Si substrate for ferroelectric
memories
*S. Horita, T. Toda, and H.
Kasagawa*

Multilayer ferroelectric
 $\text{Pb}(\text{Zr}_{0.52}\text{Ti}_{0.48})\text{O}_3$ thick films
prepared by pulsed laser deposition
process
*H.-F. Cheng, C.-S. Lin, and I.-
N. Lin*

Domain structure of epitaxial
 PbTiO_3 thin films on Pt(001)/
MgO(001) substrates
*Y.K. Kim, K. H. Ahn, K. Lee,
and S. Baik*

Microstructure and electrical
properties of $(\text{Pb},\text{La})(\text{Zr},\text{Ti})\text{O}_3$
films crystallized by one-step
postdeposition annealing using
PLZT seed layer and chemical
oxidation treatment
*R. Wakabayashi, M. Kobune, T.
Sawada, S. Kojima, and T.
Sekina*

Ferroelectric properties of
 $\text{PbZr}_{0.4}\text{Ti}_{0.6}\text{O}_3$ film on
 $\text{La}_{1/2}\text{Sr}_{1/2}\text{CoO}_3$ electrode
*J.-H. Kim, H.S. Kim, W.K.
Choo, B.J. Kuh, K.V. Im, and
S.H. Park*

Ferroelectricity of rare earth Eu

doped $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$ thin films by
a sol-gel method

*Y.J. Yu, H.L.W. Chan, F.P.
Wang, C.L. Choy, and L.C. Zhao*

Fabrication of multilayer ring
transformer
*N.Y. Wong, H.L.W. Chan, and
C.L. Choy*

Structure control of ferroelectric
 PbTiO_3 thin films using SrTiO_3
buffer layer prepared by
metalorganic decomposition
*K. Kimura, K.M.A. Salam, H.
Fukuda, and S. Nomura*

The grain boundary effect on the
hydrogen-induced degradation in
lead zirconate titanate thin films
*J.-S. Lee, J.-H. Park, J.-I. Yun,
and S.-K. Joo*

Nucleation and growth control in
PZT thin films by scanning rapid
thermal annealing process
*J.-S. Lee, J.-H. Park, J.-I. Yun,
and S.-K. Joo*

Low temperature crystallization of
lead zirconate titanate thin films by
ion damaged seed layers
*J.-H. Park, J.-S. Lee, J.-I. Yun,
and S.-K. Joo*

Characterization of PZT capacitors
with Ir electrodes successively
prepared by MOCVD
*K. Kita, H. Fujisawa, M.
Shimizu, and H. Niu*

Crystalline and ferroelectric proper-
ties of low temperature grown
 $\text{PbZr}_x\text{Ti}_{1-x}\text{O}_3$ thin films by
metalorganic chemical vapor
deposition
*M Okaniwa, H. Fujisawa, M.
Shimizu, and H. Niu*

Low temperature deposition of
 $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ thin films on amor-
phous $\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ intermediate
layer by RF sputtering
*S. Mochizuki, R. Thomas, T.
Mihara, and T. Ishida*

Effects of sol-gel derived seed
layers on the characteristics of RF
sputtered PZT thin films using
excess PbO doped
 $\text{Pb}(\text{Zr}_{0.5}\text{Ti}_{0.5})\text{O}_3$ ceramic target
*R. Thomas, S. Mochizuki, T.
Mihara, and T. Ishida*

Fabrication of cantilever structure
for piezoelectric microphone and
microspeaker
*L.-T. Zhang, T.-L. Ren, J.-S. Liu,
L.-T. Liu, and Z.-J. Li*

High quality ferroelectric capacitor
for FeRAM applications
*T.-L. Ron, L.-T. Zhang, J.-S. Liu,
L.-T. Liu, and Z.-J. Li*

Structure and ferroelectric proper-
ties of superlattices PT/PLT epitaxi-
ally grown on MgO and SrTiO_3
*C. Endo, R. Ai, K. Wasa, T.
Matsuda, A. Unno, H. Okino, and
T. Yamamoto*

Effect of RTA on the properties of
PZT thin films made by low tem-
perature MOCVD
S.-I. Kim and C.-H. Lee

Thickness dependence of the
electrical and electromechanical
properties of PZT thin films
H. Maiwa and N. Ichinose

Characteristics of ferroelectric
 $\text{Pb}(\text{Zr}_{1-x}\text{Ti}_x)\text{O}_3$ thin film capacitors
deposited on PtRhO_y electrode
barriers

IFFF 2002 PAPERS

K. Lee, K.H. Lee, and B.K. Ju

Wide process window of low-temperature deposited Pb(Zr,Ti)O₃ films by pulsed MOCVD

G. Asano, T. Oikawa, K. Okada, and H. Funakubo

Low-leakage epitaxial PZT thin film grown on In/MgO substrate by metalorganic chemical vapor deposition

T. Oikawa, K. Takahashi, J. Ishida, T. Ochiai, K. Saito, A. Sawabe, and H. Funakubo

Composition and orientation dependences of dielectric and ferroelectric properties of epitaxial PZT thin films grown by metalorganic chemical vapor deposition

T. Oikawa, K. Saito, and H. Funakubo

Fabrication of sonic sensors using PZT thin film on Si diaphragm and cantilever

S. Murakami, K. Inoue, Y. Suzuki, S. Takamatsu, T. Kitano, M. Kinoshita, K. Yamashita, and M. Okuyana

Fast deposition of lead-zirconate-titanate thick films by arc discharged reactive ion-plating method

M. Akamatsu, M. Tani, and Y. Yasuda

Effect of interface on electrical properties of thin Pb(Zr,Ti)O₃ films

Y.K. Lee, J.K. Lee, and Y.S. Park

Powder preparation for Pb(Zr_{0.52}Ti_{0.48})O₃ thick films formed by aerosol deposition method

J. Akedo and M. Lebedev

Low temperature deposition of ferroelectric Pb(Zr,Ti)O₃ thin films on Ir electrode barriers

K.H. Lee, D.H. Park, and K. Lee

Micropatterning of ferroelectric Pb(Zr_{0.3}Ti_{0.7})O₃ by photolithography and sol-gel processing

Q. Zhang and R. Whatmore

Uniformity of PZT thin films prepared by MOCVD on 8" ϕ substrate

T. Masuda, M. Kajinuma, T. Yamada, H. Uchida, M. Uematsu, K. Sun, and M. Ishikawa

Fabrication of ferroelectric micro-capacitors with self-aligned top electrodes by electron beam induced patterning process

S. Okumura, K. Suzuki, R. Takeuchi, T. Maekawa, and T. Shiosaki

Fabrication of (001) oriented PZT thin films for MEMS applications

H.-J. Zhao, T.-L. Ren, J.-S. Liu, L.-T. Liu, and Z.-J. Li

Epitaxial growth and electrical properties of Pb(Zr,Ti)O₃ thin films on SrTiO₃ (100) with an atomically flat surface by metalorganic chemical vapor deposition

H. Nonomura, H. Fujusawa, M. Shimizu, and H. Niu

Piezoelectric and ferroelectric properties of Pb(Zr,Ti)O₃ films for MEMS applications

C.-Y. Koo, S.-H. Kim, D.-S. Lee, H.-J. Woo, D.Y. Park, J. Yang, J. Ha, and C.S. Hwang

Growth stages of of sol-gel derived PZT (30/70) on Pt/Ti/SiO₂ as shown

bySPM (PFM and topography)

S. Dunn, Q. Zhang, R.W. Whatmore

Preparation of electrically stable Pb(Zr,Ti)O₃ thin films by the CSD method with a thickness down to 50nm

U. Ellerkmann, T. Schneller, U. Böttger, and R. Waser

Characterization of the residual stress in titanium/platinum and tantalum/platinum thin film electrodes used in the processing of PZT MEMS devices

R.G. Polcawich, J.P. Clarkson, J. Pulskamp, A. Wickenden, M. Wood, M. Ervin, K. Kirchner, and M. Dubey

Structural properties of PZT system film in use of pulsed laser ablation deposition

M. Ichiki, L. Zhang, Z. Wang, and R. Maeda

Growth of niobium doped PbZr_{0.52}Ti_{0.48} (PNZT) films for fabrication of a gyroscope

S. Kotru, P. Padmini, C. Nistorica, and R.K. Pandey

A comparison of rhombohedral and tetragonal PZT for FeRAM applications

A.I. Kingon, A. Gruverman, B. Rodriguez, and J.-P. Maria

Preparation of PLZT ferroelectric films by RF sputtering on 200mm ϕ substrate

S. Kikuchi, Y. Miyaguchi, T. Jimbo, I. Kimura, M. Tanimura, K. Suu, and M. Ishikawa

Low temperature of Pb(Zr,Ti)O₃

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thin films by liquid delivery
MOCVD

*M. Miyake, Y. Ueda, S. Okamura,
and T. Shiosaki*

Pb(Zr,Ti)O₃ thin films deposited by
liquid delivery MOCVD using a
single cocktail solution with
Pb(METHD)₂, Zr(METHD)₄ and
Ti(MPD)(METHD)₂

*Y. Otani, Y. Ueda, M. Miyake, S.
Okamura, and T. Shiosaki*

Dependence on reacture pressures of
Pb(Zr,Ti)O₃ films by liquid delivery
MOCVD

*Y. Ueda, M. Miyake, S. Okamura,
and T. Shiosaki*

Study of thickness dependence on
electrical properties of (Pb,La)TiO₃
thin films for memory applications

*P. Venkateswarlu, P. Victor, and
S.B. Krupanidhi*

Alternating current conduction and
impedance spectroscopy analysis on
pulsed excimer laser ablated
(Pb,La)TiO₃ thin films

*P. Venkateswarlu, P. Victor, and
S.B. Krupanidhi*

Study of relaxor behavior in
PbMg_{1/3}Nb_{2/3}O₃-PbTiO₃ thin films
grown using pulsed excimer laser
ablation technique

*L. Laha, P. Victor, and S.B.
Krupanidhi*

Deposition of thin film PZT and
constituent oxides: Chemistry,
process, and film characteristics

*B.C. Hendrix, I.-S. Chen, S.M.
Bilodeau, Z. Wang, C. Xu, T.H.
Baum, and J.F. Roeder*

Low temperature preparation of

Pb(Zr,Ti)O₃Pt/(Ti,Ni)/Si
heterostructure by laser annealing
*H.-C. Pan, H.-L. Tsai, and C.-C.
Chou*

Electrical properties of ferroelectric
Pb(Sr,Ti)O₃ films on stainless steel
substrates with La(Sr,Mn)O₃ buffer
layers

H.-C. Pan and C.-C. Chou

Preparation and electrical property
of b-PVDF/PbTiO₃ thin films

*C.M. Wang, M.C. Kao, and Y.C.
Chen*

Fabrication and electrical properties
of sol-gel derived PMNT thin films
with single perovskite phase

H. Fan and H.-E. Kim

Ferroelectric properties of PMNT
thin films epitaxially grown on La-
doped SrTiO₃

*K. Wasa, Y. Yamada, M.
Shimoda, T. Matsuda, A. Unno,
S.H. Seo, D.Y. Noh, H. Okino,
and T. Yamamoto*

Sol-gel derived Pb(Sc_{0.5}Nb_{0.5})O₃
thin films: Processing and dielectric
properties

*B.J. Kuh, W.K. Choo, K.
Brinkman, J.-H. Kim, D.
Damjanovic, and N. Setter*

Thick Pb(Ni_{1/3}Nb_{2/3})O₃(Pb_{1-x})
(Ti_{1-y}Zr_y)O₃ films prepared by tape-
casting

*N.-H. Tai, Y.-M. Shen, T. Hsu, I.-
N. Lin, L.-J. Hu, and T.-S. Yeh*

Structural evolution of perovskite
Pb(Mg_{1/3}Mb_{2/3})O₃ thin films on
SrTiO₃ and MgO substrates

*S.H. Seo, D.Y. Noh, Y. Yamada,
and K. Wasa*

Enhanced micro-actuation for
MEMS devices using PMN-30PT
thin films

*D. Jenkins, E. Fribourg-Blanc,
E. Cattani, and D. Remiens*

Compositionally modulated
Pb(Mg_{1/3}Nb_{2/3})O₃-PbTiO₃ relaxor
thin films deposited by pulsed
excimer laser ablation technique

*A. Laha, P. Victor, and S.B.
Krupanidhi*

Development of PMNT
electrostrictive thin films for bulk
actuation

*E. Fribourg-Blanc, E. Cattani, D.
Remiens, D. Jenkins, M. Dupont,
and D. Osmont*

THIN FILMS - PROPERTIES

Characteristics of BST thin films
prepared by novel chemical solution
deposition method for high density
DRAM application

Y. Lin, Y. Xie, and T. Tang

Field and time induced order-
disorder transition in "hard" PZT
thick films

*D. Damjanovic, A. Tagantsev, J.
Dorn, J. Mueller, and N. Setter*

Characteristics of low temperature
prepared (Ba,Sr)TiO₃ films post-
treated by novel excimer laser
annealing

*D.-C. Shye, B.-S. Chiou, C.-C.
Hwang, J.-S. Chen I.-W. Su, C.-
C. Chou, and H.-C. Cheng*

Effects of poling on the switching
properties of SrBi₂Ta₂O₉ films

*X.M. Lü, J.S. Zhu, X.B. Chen,
X.S. Zhang, Z.G. Liu, and Y.N.
Wang*

IFFF 2002 PAPERS

Characterization of (Ba,Sr)TiO₃ (BST) thin films grown by liquid delivery metalorganic chemical vapor deposition using a novel Ti precursor, Ti((2meip)₂

Y.J. Cho, Y.-S. Min, J.-H. Lee, J.S. Kim, J.H. Kim, and C.S. Hwang

Dielectric properties of irradiated ferroelectric and antiferroelectric thin films

R. Bittner, K. Humer, H.W. Weber, L. Cakare, A. Sternberg, D.V. Kulikov, and Y.V. Trushin

Thermally activated low frequency dielectric dispersion of antiferroelectric

Pb_{1.1}La_{0.025}Zr_{0.95}Ti_{0.05}O₃ thin film
I.W. Kim, D.S. Lee, S.H. Kang, Y.H. Kim, B.C. Choi, and J.H. Jeong

Effect of *in-situ* applied field on the properties of SrBi₂Ta₂O₉ thin film

H. Ling, A. Li, D. Wu, Z. Liu, and N. Ming

Relaxation of remanent polarization in PZT thin film capacitors

K.W. Lee and W.J. Lee

Internal strain effect on polarization profile and domain structure in ferroelectric thin films

S.V. Pavlov

Analysis of the grain size saturation in selectively nucleated and lateral crystallized lead zirconate titanate thin films

J.-S. Lee, J.-S. Park, and S.-K. Joo

Particularities of behavior of the self-polarized lead zirconate titanate thin films

V.P. Afansjev, A.V. Pankrashkin, I.P. Pronin, and L.M. Sorokin

Dielectric property and lattice distortion of BaTiO₃/SrTiO₃ superlattice by pulsed laser deposition

J. Kim, L. Kim, D. Jung, Y.S. Kim, and J. Lee

Current transport through ultra-thin PZT and BTO tunnel barriers

H. Kohlstedt, J.R. Contreras, J. Schubert, U. Poppe, C.L. Jia, and R. Waser

Effect of Zr/Ti ratio in targets in electrical properties of PZT thin films derived by laser ablation

Z.J. Wang, L.J. Yan, H. Kokawa, and R. Maeda

Ferroelectric fatigue in sol-gel derived Pb(Zr_{0.40}Ti_{0.60})O₃ thin films having Pt bottom and PtO_x top electrodes

J.E. Lim, K.S. Cho, C.S. Hwang, S.-H. Kim, D.-S. Lee, H.-J. Woo, C.-Y. Koo, and J. Ha

Heat-treatment induced ferroelectric fatigue of Pt/Sr_{1-x}Bi_{2+y}Ta₂O₉/Pt thin film capacitors

J. Zhao, S. Jeong, J. Lim, C.S. Hwang, and S.-H. Kim

Characterization of (Bi_{3.15}La_{0.85})Ti₃O₁₂ thin films fabricated by chemical solution deposition on various substrates

S.-O. Ryu, W.-J. Lee, N.-Y. Lee, K.-J. Choi, I.-K. You, S.M. Cho, B.-G. Yu, K.-I. Cho, and S.-G. Yoon

First-principles study of electronic polarization in Bi-layer structure oxides

H. Miyazawa, E. Natori, M. Ishida, T. Shimoda, and D. Vanderbilt

Property degradation of Pb(Zr_{0.52}Ti_{0.48})O₃ (PZT) thin film with thickness and aging time

H.W. Song, H. Shin, S. Kim, and K. No

Electrical and structural properties of PZT films deposited by MOCVD using ultrasonic nebulation

H.-S. Shin and C.-H. Lee

Hydrogen-induced degradation mechanisms in ferroelectric (Bi,La)₄Ti₃O₁₂ and Pb(Zr,Ti)O₃ thin films

J.-G. Yoon, S. Seo, B.S. Kang, J.D. Kim, T.W. Noh, Y.K. Lee, and Y.S. Kim

Imprint characteristics of ferroelectric thin films at high storage and operation temperatures

K.H. Noh, Y.M. Kang, B. Yang, S.W. Lee, and Y.-J. Park

Rejuvenation and fatigue effects in sol-gel PZT films with platinum electrodes

V. Shur, E. Rumyantsev, I. Baturin, E. Nikolaeva, E. Shishkin, D. Kuznetsov, D. Bolten, T. Schneller, and R. Waser

Ferroelectric properties and current conduction mechanisms of

Pt(Bi,La)₄Ti₃O₁₂/Pt capacitors
N.-K. Kim, C.-R. Song, S.-Y. Kweon, E.-S. Choi, S.-J. Yeom, and J.-S. Roh

Electrical properties of vanadium doped Bi-La-Ti-O thin films derived

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| IFFF 2002 PAPERS |
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by chemical solution deposition method

T.-W. Chiu, N. Wakiya, K. Shimozaki, and N. Mizutani

Simulation of leakage current in thin films with dead layers

H. Schroeder, S. Schmitz, P. Meuffels, and R. Liedtke

Conduction behavior of strontium-bismuth-tantalate thin films by pulsed laser deposition

J.S. Kim, T.K. Song, S.S. Kim, J.K. Kim, I.W. Kim, B.C. Choi, and J.H. Jeong

Finite element analysis of domain structures in epitaxial PbTiO_3 thin films on MgO and Pt/MgO substrates

K. Lee, Y.K. Kim, and S. Baik

Electrical properties of in-plane oriented ferroelectric $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ based thin films synthesized by chemical solution

H. Matsuda and T. Iijima

Characterization of SBT based capacitors using Zr-silicate insulator layers

H. Min, C. Jun, N. Park, S. Kong, J. Lee, and J. Kim

Influence of structural properties on the temperature of ferroelectric transition of $\text{Ba}_x\text{Sr}_{1-x}\text{TiO}_3$ films

S.F. Karamanenko, A.I. Dedyk, Y.-J. Oh, V.I. Sakharov, and I.T. Serenkov

Characterization and modeling of ferroelectric thin film integrating temperature and aging dependence

L. Cima and E. Labouré

A model for switching in ferroelectric thin films by nucleation-growth of domains with three-dimensional polarization

D. Ricinchi, Y. Ishibashi, Makoto Iwata, Liliama Mitoseriu, and Masanori Okuyama

Evaluation of PLZT thin film sputtered on Pt/IrO_x/Ir bottom electrode for ferroelectric memory application

Y. Miyaguchi, T. Jimbo, S. Kikuchi, K. Suu, and M. Ishikawa

Current-temperature characteristics of low-temperature sputtered $(\text{Ba,Sr})\text{TiO}_3$ films post-treated by rapid thermal annealing

M.W. Kuo, J.-S. Chen, B.C.S. Chou, D.-C. Shye, C.-K. Jan, M.-F. Wu, H.-Y. Tseng, B.-S. Chiou, and H.-C. Cheng

Electrically activated rejuvenation of retention in thermally imprinted PLZT capacitors

S. Sun

Aging effect in sol-gel derived lead zirconate titanate thin films

R.S. Katiyar, A. Dixit, and S.B. Majumder

Correlation between microstructure and local ferroelectric properties of non-c-oriented epitaxial $\text{SrBi}_2\text{Ta}_2\text{O}_9$ thin films

C. Harnagea, A. Pignolet, M. Alexe, D.N. Zakharov, H.N. Lee, and D. Hesse

Resistance degradation of acceptor doped $\text{Pt/Ba}_{0.7}\text{Sr}_{0.3}\text{TiO}_3/\text{Pt}$ thin film capacitors

R. Liedtke, R. Meyer, and R. Waser

Polarization state instability in single grains of $\text{Pb}(\text{Zr}_{0.45}\text{Ti}_{0.55})\text{O}_3$ thin films

E.L. Colla, K. Torii, S. Hiboux, H.W. Song, I. Stolichnov, A. Tagantsev, K. No, and N. Setter

Tracer isotope studies of ionic defect redistribution during imprint and fatigue testing of PZT thin films

L.F. Schloss and P.C. McIntyre

Physical properties of MOD derived $\text{Bi}_4\text{Ti}_3\text{O}_{12}/\text{Bi}_2\text{SiO}_5/\text{Si}$ structures

M. Yamaguchi, T. Nagatomo, and Y. Masuda

Asymmetric dielectric and ferroelectric behavior of CSD ultra-thin $\text{Sr}_{0.8}\text{Bi}_{2.2}\text{Ta}_2\text{O}_9$ thin films

R. Jiménez, C. Alemany, A. González, M.L. Calzada, and J. Mendiola

Specific heat and thermal conductivity of BaTiO_3 polycrystalline thin films

B.A. Strukov, S.T. Davitadze, S.N. Kravchun, B.M. Goltzman, V.V. Lemanov, and S.G. Shulman

A metal-ferroelectric-semiconductor field-effect transistor memory cell

M.A. Bailey and F.D. Ho

Effects of substrates on alkoxy-derived $(\text{Y,Yb})\text{MnO}_3$ thin films

K. Suzuki, D. Fu, K. Nishizawa, T. Miki, and K. Kato

Ferroelectric properties of CSD-derived $\text{Sr}_{0.3}\text{Ba}_{0.7}\text{Nb}_2\text{O}_6$ (SBN30) thin films

D.G. Lee, H.Y. Lee, J.J. Kim, and S.H. Cho

Ferroelectric and magnetic properties of $\text{PtFeO}_3\text{-PbTiO}_3$ thin films

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| IFFF 2002 PAPERS |
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C.I. Cheon, J.S. Kim, and P.W. Jang

Characterization of potassium niobate produced by self-assembled nanosheet from aqueous solution

K. Toda, N. Ohtake, M. Kawakami, S. Tokuoka, K. Uematsu, and M. Sato

Dielectric relaxation in pulsed excimer laser ablated amorphous zirconium titanate thin films

P. Victor and S.B. Krupanidhi

Impact of microstructure on the electrical properties of zirconium titanate thin films in MOS configuration

P. Victor and S.B. Krupanidhi

Influence of excitation frequency and amplitude on the switching properties of SBT and PZT thin films at 10MHz hysteresis frequency

U. Kall, U. Bottger, Y.-K. Lin, A. Werner, R. Waser, C. Szot, and S. Tiedke

THIN FILM - FABRICATION - BIT SYSTEM

Effect of heat treatment on electric properties of $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ thin films by two-dimension RF magnetron sputtering

K. Kudoh, T. Higuchi, M. Tanaka, and T. Tsukamoto

$\text{Bi}_{3.99}\text{Ti}_{2.97}\text{O}_{12}$ ferroelectric thin films by pulsed laser deposition

D.-Y. Wang, J.-S. Zhu, H.L.-W. Chan, and C.-L. Choy

Effect of niobium doping on the ferroelectric properties of bismuth

titanate

Z.H. Bao, Y.Y. Yao, X.M. Lü, J.S. Zhu, and Y.N. Yang

La doped effect on the fatigue properties of $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ - $\text{SrBi}_4\text{Ti}_4\text{O}_{15}$ thin films

J.S. Zhu, D.Y. Wang, H.X. Qin, Z.H. Bao, D. Su, Y. Ding, X.M. Lü, H.L.W. Chan, and C.L. Choy

Structural and electrical properties of $\text{Bi}_{3.25}\text{La}_{0.75}\text{Ti}_3\text{O}_{12}$ thin films for memory applications

D. Wu, A. Li, Z. Liu, and N. Ming

Doping effects on the properties and microstructure of the intergrowth $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ - $\text{SrBi}_4\text{Ti}_4\text{O}_{15}$ thin films

H. Qin and R.A. Gerhardt

Dependence of metal composition of BLT thin films prepared by MOCVD on metalorganic precursors

Y. Tasaki, T. Tanaka, T. Hashimoto, T. Yamamoto, T. Nittamchi, and S. Yoshizawa

Effect of metalorganic precursors on the morphology of BLT thin films prepared by MOCVD

T. Tanaka, S. Yoshizawa, T. Hashimoto, T. Yamamoto, and Y. Tasaki

Effect of V-substitution on the ferroelectric properties of $\text{Bi}_4\text{Ti}_3\text{O}_3$ - PbTiO_{12} and $(\text{Bi},\text{M})_4\text{Ti}_3\text{O}_{12}$ [M = lanthanoid] films fabricated by chemical solution deposition technique

H. Uchida, H. Yoshikawa, I. Okada, H. Matsuda, T. Iijima, T. Watanabe, and H. Funakubo

Microstructures and ferroelectric

properties of $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ thin films prepared by sol-gel method

J.K. Kim, S.S. Kim, E.K. Choi, J.S. Kim, and T.K. Songa

Ferroelectric properties of donor-doped $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ thin films prepared by sol-gel process

S.S. Kim, J.K. Kim, E.K. Choi, B.S. Kim, and T.K. Song

Preparation and properties of $\text{Bi}_{4-x}\text{La}_x\text{Ti}_3\text{O}_{12}$ ferroelectric thin films using excimer UV irradiation

T. Hayashi, D. Togawa, M. Yamada, W. Sakamoto, and S. Hirano

Preparation and characterization of site-engineered $\text{Bi}_4\text{Ti}_3\text{O}_{12}$ based thin films by MOCVD

T. Watanabe, T. Kojima, T. Sakai, H. Funakubo, M. Osada, K. Saito, Y. Noguchi, and M. Miyayama

Large remanent polarization of $(\text{Bi},\text{Nd})_4\text{Ti}_3\text{O}_{12}$ epitaxial thin films grown by metalorganic chemical vapor deposition

T. Kojima, T. Sakai, T. Watanabe, and H. Funakubo

Direct crystallization and characterization of $\text{Bi}_3\text{TiTaO}_9$ and $\text{Bi}_{3-x}\text{La}_x\text{TiTaO}_9$ thin films prepared by MOCVD

M. Suzuki, M. Masatoshi, N. Nukaga, T. Watanabe, N. Hajime, T. Takenaka, and H. Hunakubo

Orientation control of $(\text{Bi},\text{La})_4\text{Ti}_3\text{O}_{12}$ thin films by addition of silicates and germanates

Y. Kawashima, T. Kijima, and H. Ishiwara

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| IFFF 2002 PAPERS |
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Multi-step growth of oriented LiNbO₃ thin films

V. Bormand, I. Huet, and P. Papet

Dielectric and tunable properties of Ba_{0.96}Ca_{0.04}Ti_{0.84}Zr_{0.16}O₃ (BCTZ) on MgO and SiO₂/Si substrates

T.S. Kalkur, W.C. Yi, E. Philofsky, and L. Kammerdiner

Microstructural and surface morphological evolutions in compositionally graded (Ba_{1-x}Sr_x)TiO₃ thin films and related dielectric properties

X. Zhu, H. L.-W. Chan, C.-L. Choy, and K.-H. Wong

Dielectric properties and microstructures of (Ba_{1-x}Sr_x)TiO₃ epitaxial thin films with compositional gradients normal to the substrates

X. Zhu, H. L.-W. Chan, C.-L. Choy, and K.-H. Wong

Planar dielectric properties of compositionally graded (Ba_{1-x}Sr_x)TiO₃ thin films prepared by pulsed-laser deposition

X. Zhu, H. L.-W. Chan, C.-L. Choy, and K.-H. Wong

Growth of stoichiometric LiNbO₃ thin films through metalorganic decomposition process

H. Zhang, X. Wang, and T.A. Rabson

Low-temperature preparation of ferroelectric Ba₂NaNb₅O₁₅ thin films by pulsed laser deposition

K. Ohnuki, M. Takayasu, T. Higuchi, and T. Tsukamoto

Heteroepitaxial growth of MgO thin films on Al₂O₃ (001) by

metalorganic chemical vapor deposition

W.I. Park, D.H. Kim, and G.-C. Yi

Preparation of barium strontium titanate thin film by spray deposition

Y. Takeshima, K. Nishita, K. Tanaka, and Y. Sakabe

Effect of SBN self-template layer on the structural properties of sol-gel derived Sr_{0.6}Ba_{0.4}Nb₂O₆ films

A.-D. Li, C.L. Mak, K.H. Wong, M.M.T. Ho, M.K. Yeung, D. Wu, and N.-B. Ming

Formation of epitaxial BaTiO₃/SrTiO₃ multilayers grown on Nb-doped SrTiO₃ (001) substrates

A. Visinui, M. Alexe, H.N. Lee, D.N. Zakharov, D. Hesse, and U. Gösele

Dielectric and pyroelectric properties of ferroelectric thin films

M.D. Glinchuk, E.A. Eliseev, and V.A. Stephanovich

Growth morphology and crystal orientation of KNbO₃ on SrTiO₃ by liquid phase epitaxy

K. Kakimoto, S. Ito, I. Masuda, N. Adachi, H. Ohsato, and T. Okuda

Crystal growth and interfacial characterization of dielectric (Ba,Zr)O₃ thin films on Si substrates

Y. Kitano, T. Matsui, N. Fujimura, K. Morii, and T. Ito

Synthesis of high dielectric constant titanium oxide thin films by metalorganic decomposition

S. Maeda, K.M.A. Salam, H. Fukuda, and S. Nomura

Effect of additive elements on improvement of the dielectric properties of Ta₂O₅ films formed by metalorganic decomposition

K.M.A. Salam, H. Fukuda, and S. Nomura

Microstructure and electrical properties of (BaSr)TiO₃ thin films prepared by a sol-gel method

T.-L. Ren, X.-N. Wang, J.-S. Liu, H.-J. Zhao, T.-Q. Shao, L.-T. Liu, and Z.-J. Li

Ferroelectric characterization of Bi-modified YMnO₃ thin films grown by pulsed laser deposition for metal-ferroelectric-insulator-semiconductor (MFIS) structure

T. Choi, S.H. Shin, Y.S. Kim, and J. Lee

Fabrication and characteristic of Mn(II)- and Mn(IV)-doped BST thin films

J.-B. Bao, T.-L. Ren, J.-S. Liu, X.-N. Wang, L.-T. Liu, and Z.-J. Li

Ferroelectric Na_xK_{1-x}NbO₃ thin films on SiN_x/Si substrates by metalorganic chemical vapor deposition

C.-R. Cho

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| <p>The rest of the IFFF 2002 poster presentations will be listed in the Fall 2002 Ferroelectricity Newsletter</p> |
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UPCOMING MEETINGS**2nd Canada-US Workshop on Smart Materials and Structures
10 - 11 October 2002
Montreal, Quebec, Canada**

CanSmart, the Canadian Smart Materials and Structures Group, is pleased to announce the 2nd Canada-US Workshop on Smart Materials and Smart Structures and their applications. The workshop will be held on 10 - 11 October 2002 in Montreal, Quebec, Canada.

Since its inception in 1997, one of the CanSmart Group objectives has been to promote the emerging technologies of smart materials and structures in Canada by organizing an annual workshop on the subject. Recognizing the considerable development of this novel technology in the United States under the leadership of the federal government and its agencies, as well as the pressing need for the promotion of Canadian research and its coordination with US activities, the CanSmart Group organized the Canada-US Workshop on Smart Materials and Structures in 2001. This workshop was well received and it has now been decided that a second workshop will be held in 2002.

The workshop is planned to provide the scientific community with a forum to interact, network, and explore the potential of possible collaborations on projects of mutual interest. Special sessions featuring representatives from different governments and agencies will present the current outlook on smart materials, structures, and technologies for civilian and defense applications.

Topics

- Smart materials and composites, attached or embedded smart sensors and actuators
- Microelectromechanical systems and devices
- Shape memory alloys and active materials
- Structural vibration suppression and smart damping techniques
- Intelligent processing of materials
- Structural health monitoring
- NDE of materials and structures
- Industrial/commercial defense applications, space, aerospace, automation, medicine, civil engineering, and marine industries

Exhibition

An exhibition will take place during the workshop. Booth space is available for companies and institutions wishing to display their products and services and to develop new partnerships.

Workshop Chairs

- Janet Sater, Institute for Defense Analysis, Virginia, USA
- Gary Anderson, US Army Research Office, North Carolina, USA
- George Akhras, Royal Military College of Canada

Contact

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email: akhras@cansmart.com

www.cansmart.com

UPCOMING MEETINGS

Non-Volatile Memory Technology Symposium 2002 (NVMTS2002)**4 - 6 November 2002****Honolulu, Hawaii, USA**

The demands for storage technology are ever increasing, burdening designers of systems and components alike to bring ingenuity to the next level. How long can the demand for breakthrough developments keep going? What's around the corner? And where will it take us?

Recent seminars and symposia tended to focus on one technology over another. This symposium, however, is aimed at distilling information about all technologies to users, inventors, and investors alike.

This symposium is organized with three intents:

- To inform and update the users of non-volatile memory technology with the recent breakthroughs and advances.
- To make evident the needs and desires of such technology in light of NASA and DoD functions and missions (terrestrial, space, deep space) and to make evident the funding sources available.
- To encourage and establish a dialogue between the manufacturers of technology and the users of it.

Topics

- Memory cell design
- Materials and processing
- Environmental effects/radiation
- Device architecture and applications
- Packaging
- Integrated design/system on chip
- New concept
- Scalability

Industrial Exhibit

Parties interested in participating in an industrial exhibit should contact

Ms. Pat McLane

JPL Conference Administration

+818-354-5556

<http://nvm.jpl.nasa.gov/>

15th International Symposium on Integrated Ferroelectrics (ISIF 2003)**9 - 12 March 2003****Colorado Springs, Colorado, USA**

The science of ferroelectric thin films and their technological applications have experienced rapid and substantial progress. The worldwide increase in practical commercial applications is a sign of both the maturity of the field and the acceptance the technology has achieved.

The field of ferroelectric/piezoelectric materials is still growing rapidly due to the potential applications in MEMS technologies and the development of new generations of DRAMs.

This symposium will address topics including pyroelectric sensors, integrated high frequency devices, electrooptical components, nanotechnology, and the research and exploitation of nanosize effects.

Topics

- Circuits and devices
- Device integration issues
- Microwave devices
- Modeling and theory

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| UPCOMING MEETINGS |
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| <ul style="list-style-type: none"> • DRAMs and materials • FeRAMs and materials • Ferroelectrics for space applications • Field effect devices • Graded ferro devices • High frequency devices • High-k and gate oxides • Integrated sensors | <ul style="list-style-type: none"> • Nanosize effects • Nonvolatile memory applications • Novel characterization • Piezoelectric and MEMS applications • Pyroelectric/IR and optical applications • Testing and characterization • Thin films |
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Organization/Company Exhibits

If your organization or company would like to sponsor an exhibit or display during the symposium, please send your display proposal to Kerry Baugh at the ISIF office in Colorado Springs.

Contact

Kerry Baugh, Symposium Coordinator
 University of Colorado at Colorado Springs
 1867 Austin Bluffs Parkway, Suite 101, P.O. Box 7150, Colorado Springs, CO 80933-7150 USA
 kerry@isif.net +719-262-3488

**3rd Asian Meeting on Electroceramics (AMEC-3)
 29 June - 4 July 2002
 Singapore**

The 3rd Asian Meeting on Electroceramics (AMEC-3), which is the co-symposium E: Electronic and Advanced Ceramics of the International Conference of Materials for Advanced Technology 2003 (ICMAT-2003) and IUMRS-International Conference in Asia (ICA 2003), will be held on 29 June - 4 July 2003 in Singapore.

This AMEC-3 international conference will continue the great initiative and momentum of AMEC 1 & 2 and ICMAT 2001 & IUMRS-ICA, strengthen research and development activities in electroceramics in Asia and in the world, connect academic scholars with industrial researchers, and promote AMEC as a true international forum in this increasingly important area.

The scientific program will include invited and contributed presentations on theory, experiments, and applications of electroceramics.

Topics

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| <ul style="list-style-type: none"> • Microwave dielectrics and applications • Thin film and tunable ceramics and devices • Multilayer electronic ceramics and devices • Dielectric ceramics for electronic devices • Ferroelectric, pyroelectric, and piezoelectric ceramics and applications • Ferroelectric thin films for memories and devices • High-k dielectrics for Si electronics • Ceramic superconductors and applications • Magnetic ceramic materials and applications • Optical ceramics, single crystals, and applications | <ul style="list-style-type: none"> • Nanostructured ceramics, single crystals and applications • Glass, ceramic polymer composites and devices • Porous ceramic materials • Crystal chemistry of functional materials • Sensor, actuator, and transducer applications • Advanced ceramic MEMS and microtechnology • Electronic and optical packaging • Processing, sintering, microstructures and interfaces • Phase diagram, nonequilibrium and metastable state • Theory, modeling, and design of ceramics • Measurement and characterization |
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UPCOMING MEETINGS

- Conductive ceramics, NTC & PTC varistors, battery, and fuel cell

Contact

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50 Nanyang Ave., Singapore 639798
fax: +65-6792-0415; email: ewzhu@ntu.edu.sg
<http://amec-3.ntu.edu.sg>

Polar Oxides: Properties, Characterization and Imaging
8 - 11 June 2003
Capri, Italy

The field of polar oxides is experiencing a considerable expansion in recent years. New materials and new processing technologies are enlarging the offer of highly performing materials for a large range of device applications under wide operation conditions. The meeting **Polar Oxides: Properties, Characterization and Imaging** is a forum for users and designers, researchers, developers, and producers. The aim is to review, discuss, and assess the properties of the materials under the aspects of new and advanced characterization and imaging techniques.

Invited oral presentations by experts in the field will have the form of comprehensive and updated reviews. Contributed papers aim at informing the participants of recent scientific and technological developments in the field. These contributions are introduced during the poster session.

Contact

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<http://www.emrl.de>

4th Asian Meeting on Ferroelectrics 2003
14 - 17 December 2003
Bangalore, India

Topics

- Theories and fundamental phenomena of ferroelectrics
- Novel materials and experimental techniques
- Crystals and ceramics
- Ferroelectric polymers and composites
- Glass and amorphous systems, nanostructures
- Dielectric, piezoelectric, and pyroelectric properties
- Optical properties and nonlinear phenomena
- Domains and boundaries
- Integrated piezoelectric/electrostrictive MEMS
- Surfaces, interfaces, and defects
- Relaxor ferroelectrics
- Processing of ferroelectric materials

UPCOMING MEETINGS

- Ferroelectric thin films and memory devices
- Applications: Sensors, actuators, transducers, and microwave devices
- Ferroelectrics and microelectromechanical systems (MEMS)
- Electrooptics, displays, and infrared imaging
- Energy storage, wireless communications, and optical data storage

General Chair

Prof. S.B. Krupanidhi

Secretary

Dr. S. Gopalkrishnan

Contact

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FORMATION OF BOARD OF ASIAN FERROELECTRIC ASSOCIATION

The Asian Ferroelectric Association (AFA) was initiated in 1993 during the Eighth International Meeting on Ferroelectrics (IMF-8) in Gaithersburg, USA. Delegates from China, India, Hong Kong, Japan, Korea, Singapore, Taiwan, and USA gathered to discuss setting up a regional forum of ferroelectrics to promote studies in Asia on ferroelectrics and related phenomena. All the delegates agreed to establish the AFA as a communication and coordinating channel of the ferroelectric community of the region and initiate the series of Asian Meetings on Ferroelectrics. Professor Yao Xi of China was elected founder-chairperson of the Asian Ferroelectric Association.

The First Asian Meeting on Ferroelectrics (AMF-1) was held at Xian, China, in October 1995 with 185 participants from 12 countries and regions. The Second Asian Meeting on Ferroelectrics (AMF-2) was held at Singapore in December 1998 with 203 registered participants from 22 countries and regions. The Third Asian Meeting on Ferroelectrics (AMF-3) was held at Hong Kong in December 2000 with 450 participants from five continents. These figures not only testify to the success of the AMF, but also give a clear indication of the strong growth and rapid development of ferroelectric research activities in Asia. The Fourth Asian Meeting on Ferroelectrics (AMF-4) will be held at Bangalore, India, in December 2003. From the excellent response and participation of delegates from Asian and Western countries, it is evident that AMF has become not just a regional forum for the Asian ferroelectric community but has effectively become an international forum.

Following the success of the AMFs, the Board of the Asian Ferroelectric Association has recently been formed to better serve the ferroelectric community of the region. The AFA Board is well represented by members from the Asian countries as well as from Europe and USA, namely: Bhalla, A. S. (USA), Chan, Helen L. W. (Hong Kong), Gerhard-Multhaupt, R. (Germany), Jang, M. S. (Korea), Ichinose, N. (Japan), Lang, S. (Israel), No, K. S. (Korea), Safari, A. (USA), Setter, N. (Switzerland), Shiosaki, T. (Japan), Takenaka, T. (Japan), Tseng, Tseung Yuen (Taiwan), Yao, Xi (China), Yin, Qingrui (China), Zhong, Weilie (China), Zhu, Weiguang (Singapore). Two additional board members from India are to be added in due course. Professor Yao Xi is the Chair of the Board.

Eminent scientists with international reputation in the field have been invited to serve as advisors of the AFA Board. They are Cross, L. E. (USA), Fousek, J. (Czech), Ishibashi, Y. (Japan), Kwun, S. I. (Korea), Newnham, R. E. (USA), Scott, J. F. (UK), Yin, Zhiwen (China).

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CALENDAR OF EVENTS 2002

Aug 25-28 • Electroceramics VIII Conference, Rome, Italy (see *Ferroelectricity Newsletter*, Vol.9, No. 4, p. 17)

Sep 2-5 • 6th European Conference on Applications of Polar Dielectrics (ECAPD-6), Aveiro, Portugal
(see *Ferroelectricity Newsletter*, Vol.10, Nos. 1/2, p. 37)

Sep 15-19 • 7th International Symposium on Ferroic Domains and Mesoscopic Structures (ISFD-7),
Peninsula of Giens, French Riviera (see *Ferroelectricity Newsletter*, Vol.9, No. 4, p. 18)

Oct 10-11 • 2nd Canada-US Workshop on Smart Materials and Structures, Montreal, Quebec, Canada
(see p. 19)

Nov 4-6 • Non-Volatile Memory Technology Symposium 2002 (NVMTS2002), Honolulu, Hawaii, USA
(see p. 20)

2003

Mar 9-12 • 15th International Symposium on Integrated Ferroelectrics (ISIF 2003), Colorado Springs, Colorado,
USA (see p. 20)

Jun 8-11 • Polar Oxides: Properties, Characterization and Imaging, Capri, Italy (see p. 22)

Jun 29-
Jul 4 • 3rd Asian Meeting on Electroceramics (AMEC-3), Singapore (see p. 21)

Aug 3-8 • 10th European Meeting on Ferroelectricity (EMF2003), Cambridge, UK (see *Ferroelectricity
Newsletter*, Vol.10, Nos. 1/2, p. 38)

Dec 14-17 • 4th Asian Meeting on Ferroelectrics 2003, Bangalore, India (see p. 22)